
Drill-down Analysis with Equipment Health Monitoring

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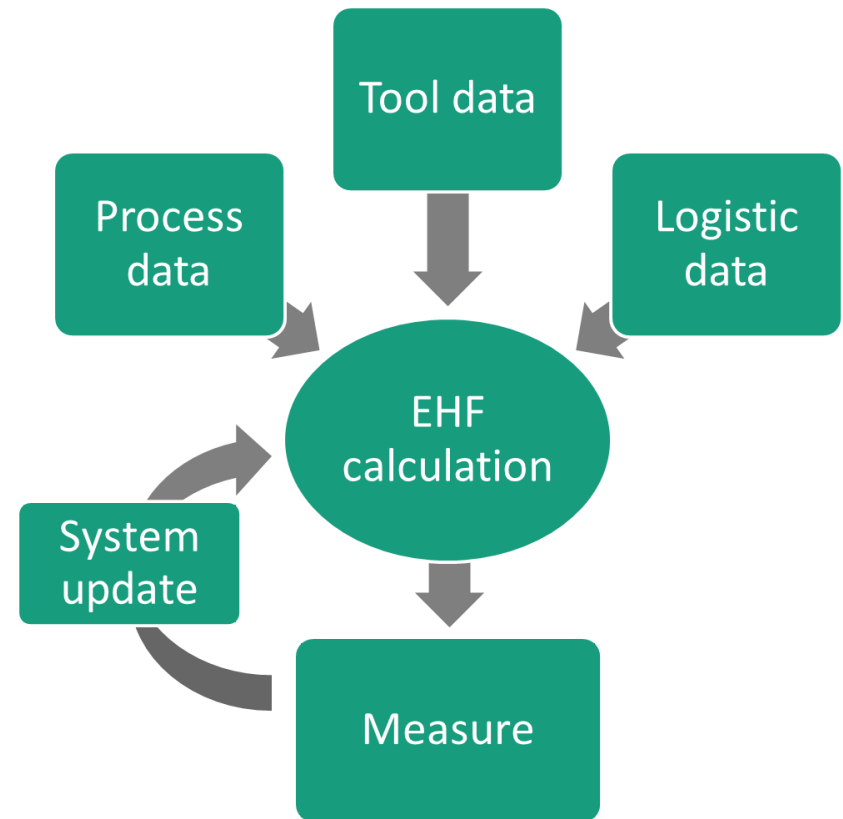
Outline

- I. Motivation
- II. Feature extraction
- III. Feature selection
- IV. EHF calculation
- V. Application example
- VI. Conclusion

I. Motivation

Definition: Equipment health factor

- Key indicator for monitoring of equipment state
- Based on process/tool, logistic and metrology data
- Utilization of historical data for training of EHF system
- Related key words
 - Equipment health monitoring
 - Equipment fingerprinting
 - Health index
 - EHF



Goal of the determining EHF is to enable...

- **Dynamic Sampling**

Sampling rate is flexible and adjusted to the machine state.

- **Material flow of critical products**

The production of critical products (important customers lots, urgent jobs, etc.) is planned only on machines which have a good system state.

- **Predictive Maintenance (PdM) based on condition monitoring**

The PdM offers cost savings over time-based preventive maintenance, because maintenance actions are performed only when necessary.

Application of the EHF

- Good machine state – EHF is high
 - ➔ Lower lot sampling rate, important lots will preferably be scheduled to run on this machine
- Machine state not ideal – EHF decreases
 - ➔ More frequent lot sampling, important lots might be scheduled to run on another tool
- “bad” machine state – EHF drops below certain limit
 - ➔ Schedule maintenance

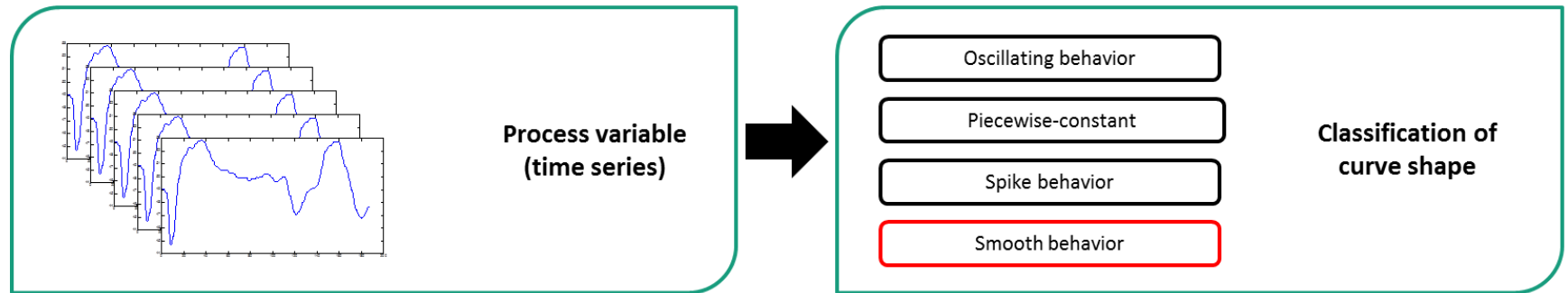
Related work

- Utilization of sensors for simple measurement of wear
- Detection of failures based on key indicators
- Usually only implemented for specific failure classes
- No general method for detection of unknown failures

- **Our objective:**
 - Improved preprocessing method to find unknown failures
 - Use of various feature extraction methods dependent on curve shape
 - Express the current equipment condition
 - Generic concept transferable to other processes

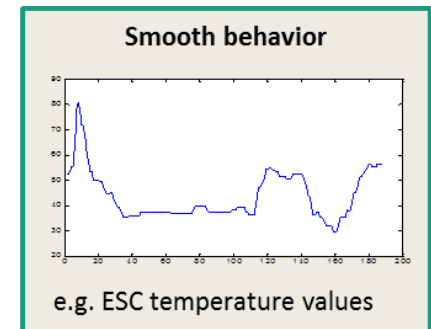
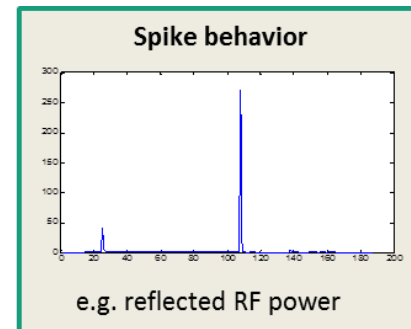
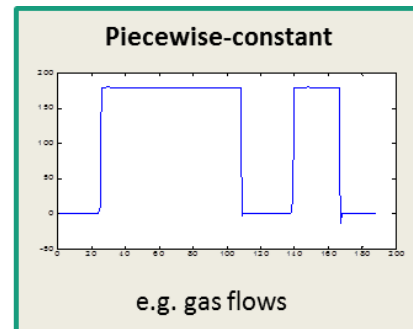
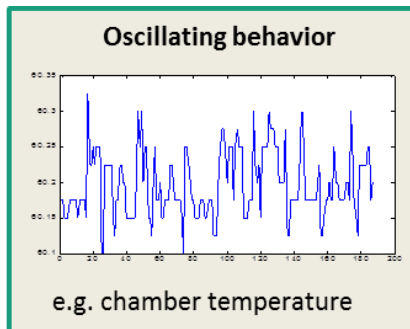
II. Feature extraction procedure

Classification of curve shape



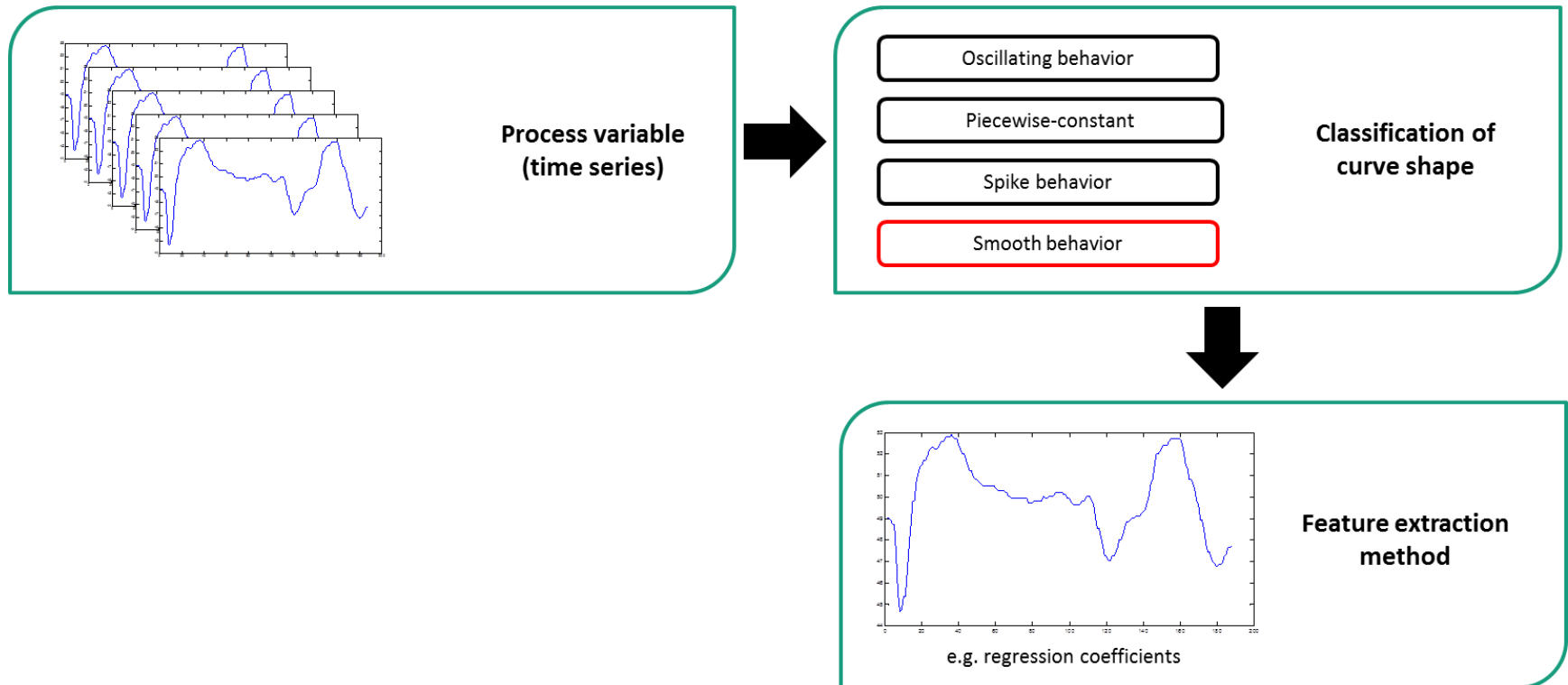
Defined variable types

- **Oscillating behavior:** trajectories with periodic variation around a central value
- **Piecewise-constant:** rectangular shaped pulses
- **Spike behavior:** most data points are close to zero with occasional peaks
- **Smooth behavior:** data with little change in their point to point value, the derivation showing only small differences in the gradient



II. Feature extraction procedure

Feature extraction method



Types of feature extraction

- **Simple key features**
 - Mean, median, standard deviation and range
- **Structural features**
 - Descriptive statistics of trajectories
- **Dynamic time warping**
 - Euclidean-distance-based similarity measurement technique
- **Frequency and time-frequency analysis**
 - Analysis in frequency domain instead time domain
- **Statistical analytical methods**
 - e.g. regression coefficients or residual analysis

Extracted features

Oscillating behavior

- Periodicity
- Trend
- Simple key features

Piecewise-constant

- Number of pulses
- Amount of Under-/Overshoots
- Maximum Overshoot
- Area under a pulse

Spike behavior

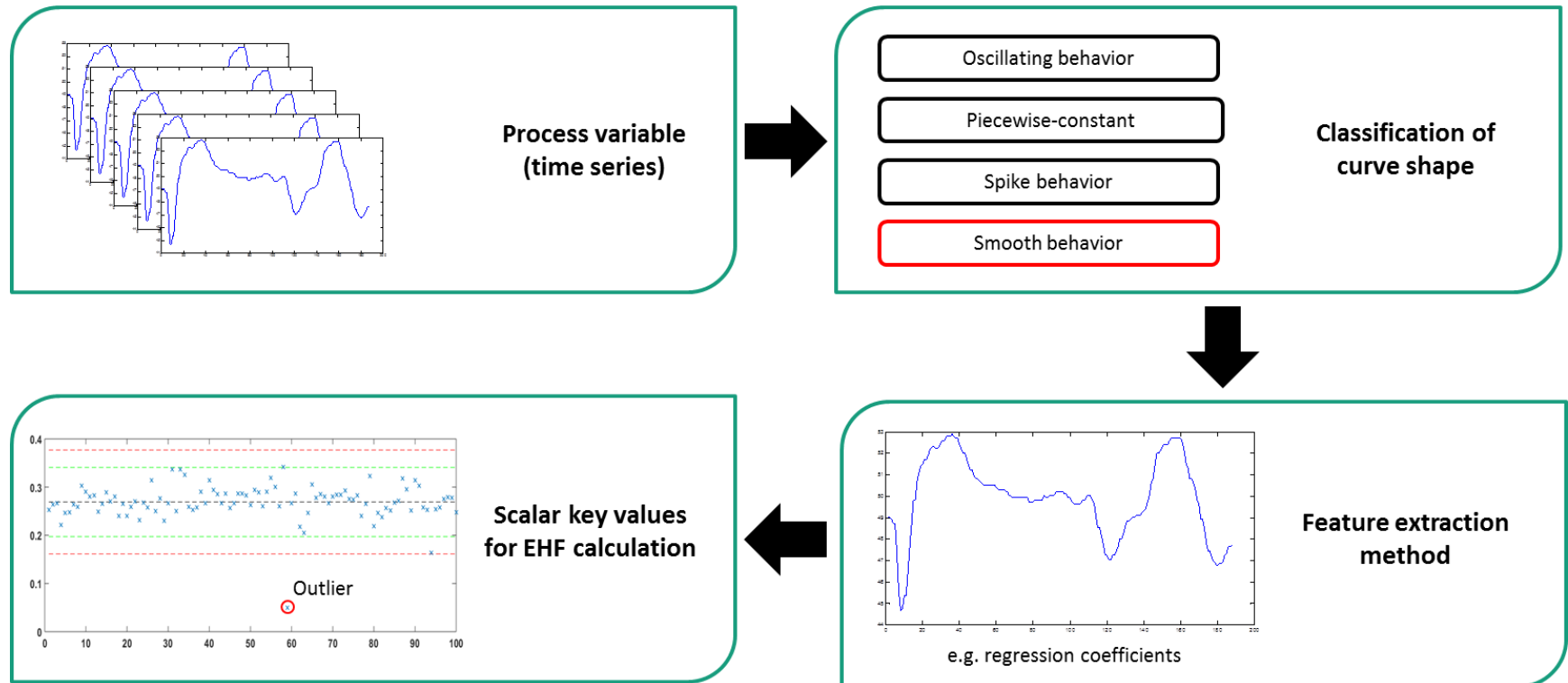
- Number of peaks
- Peak width
- Area under a peak
- Distance of peaks

Smooth behavior

- Wavelet-based correlation coefficient
- Root mean square of residuals
- Area under curve

II. Feature extraction procedure

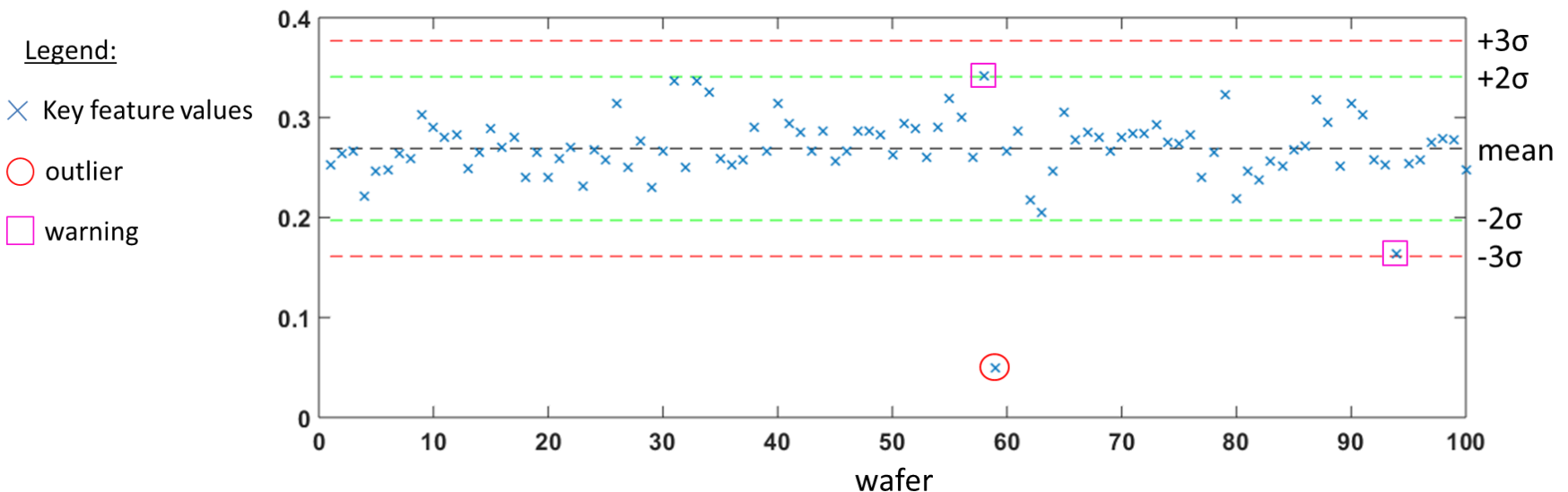
Computation of scalar key values



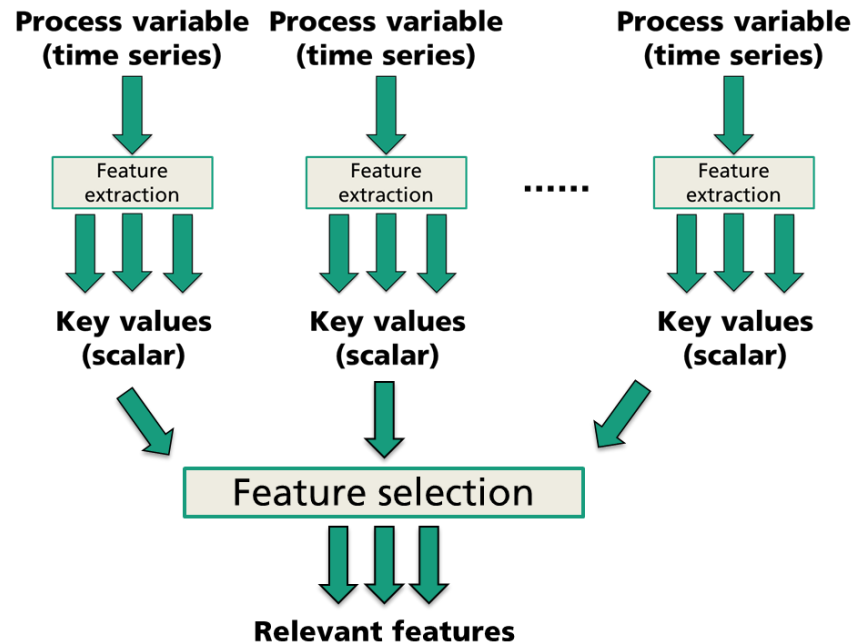
Feature factor

From feature values to scalar key value

- Feature factor is a scalar value between one and zero and reflects the state of a considered key feature in a specific time window
- Computation is based on the statistical process control (SPC)
- $$\text{Feature factor} = 1 - \frac{0,01 \times \text{Warnings} \times 100}{\text{Number of Samples}} - \frac{0,1 \times \text{Outliers} \times 100}{\text{Number of Samples}} = 0,88$$

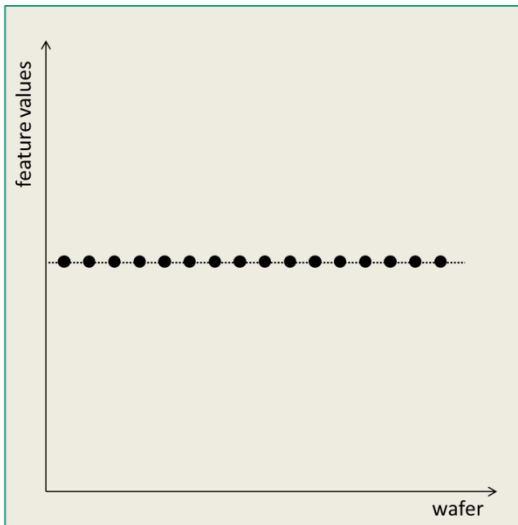


III. Feature selection



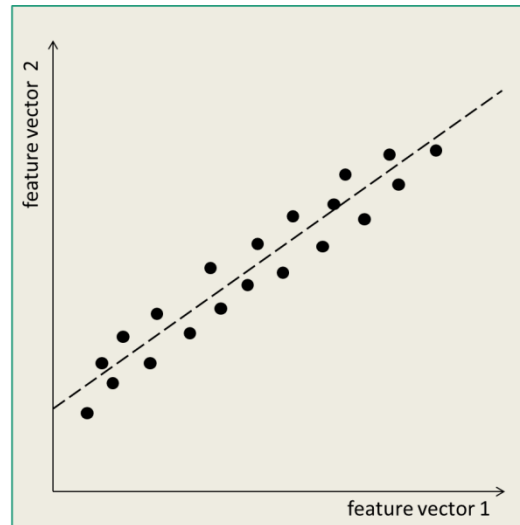
Selection criteria

*Invariant
feature vector*



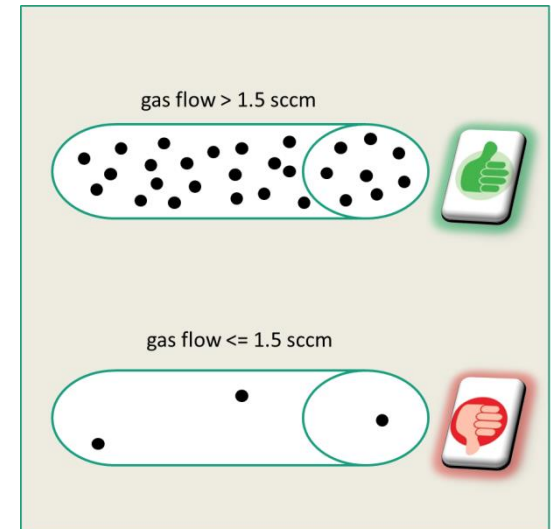
feature vector is excluded

*feature vectors
 $|r| \geq 0.85$*



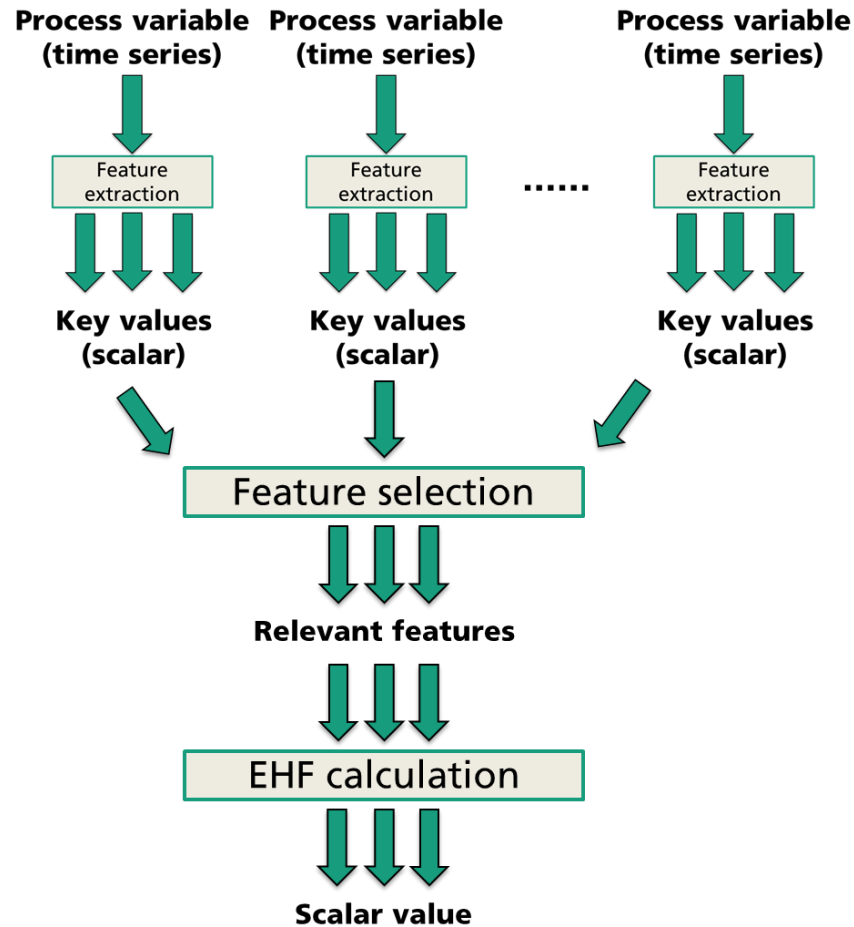
only one feature vector is
considered

gas flow ≤ 1.5 sccm



feature vector is excluded

IV. EHF calculation



Former approaches to calculate an EHF

- EHF as output of the averaging of all relevant parameters:

$$\frac{\text{Feature Factor} + \text{Feature Factor} + \text{Feature Factor} + \dots + \text{Feature Factor}}{\text{Number of Feature Factors}} \times 100$$

- EHF by multiplying all characteristic values:

$$\text{Feature Factor} \times \text{Feature Factor} \times \text{Feature Factor} \times \dots \times \text{Feature Factor}$$

Comparison of former EHF calculation options

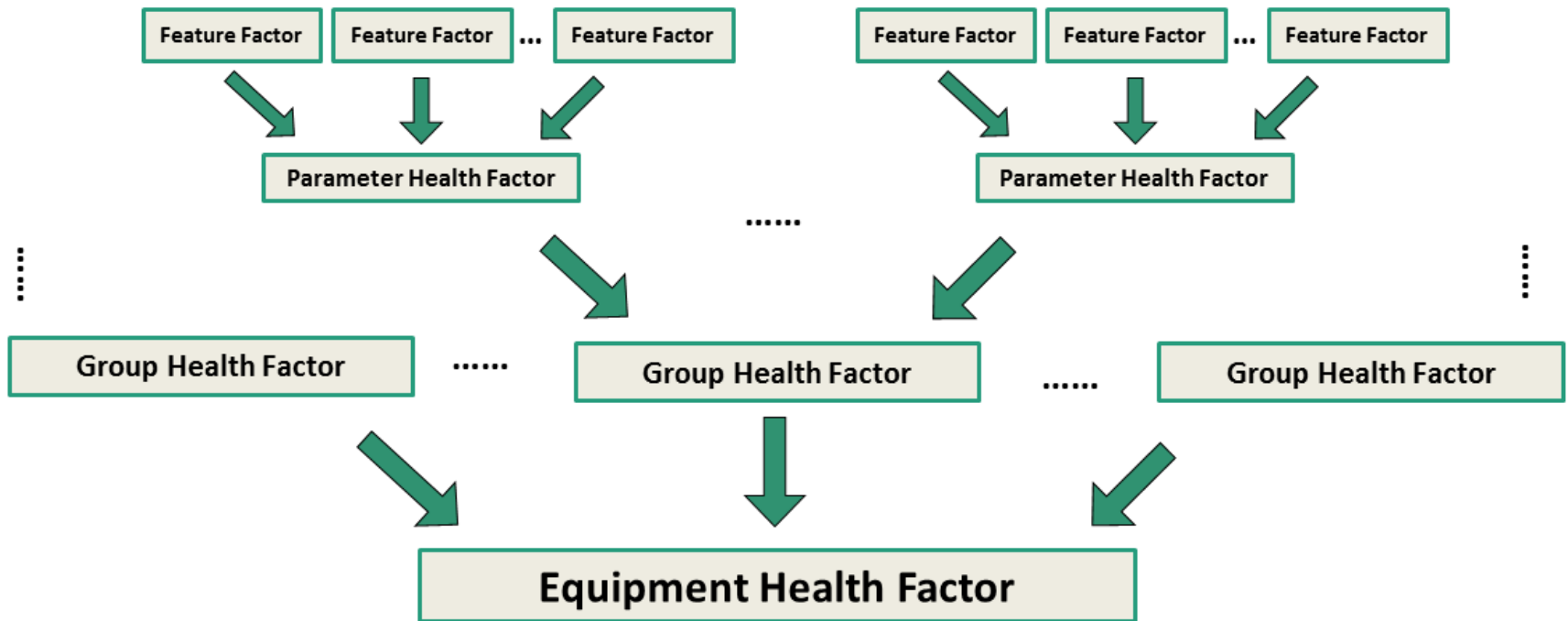
EHF as average

- Average tool state is depicted
- Bad parameters can not be detected easily
- The system status will not be set to zero even though one of the key features is beneath the wear limit
- Easier decision making whether the equipment meets the requirements or not

EHF as multiplication

- Average machine state is not identifiable
- If only one factor is equal zero the whole EHF is set to zero
- Difficult to interpret by a high amount of key features → EHF is close to zero

New EHF calculation structure

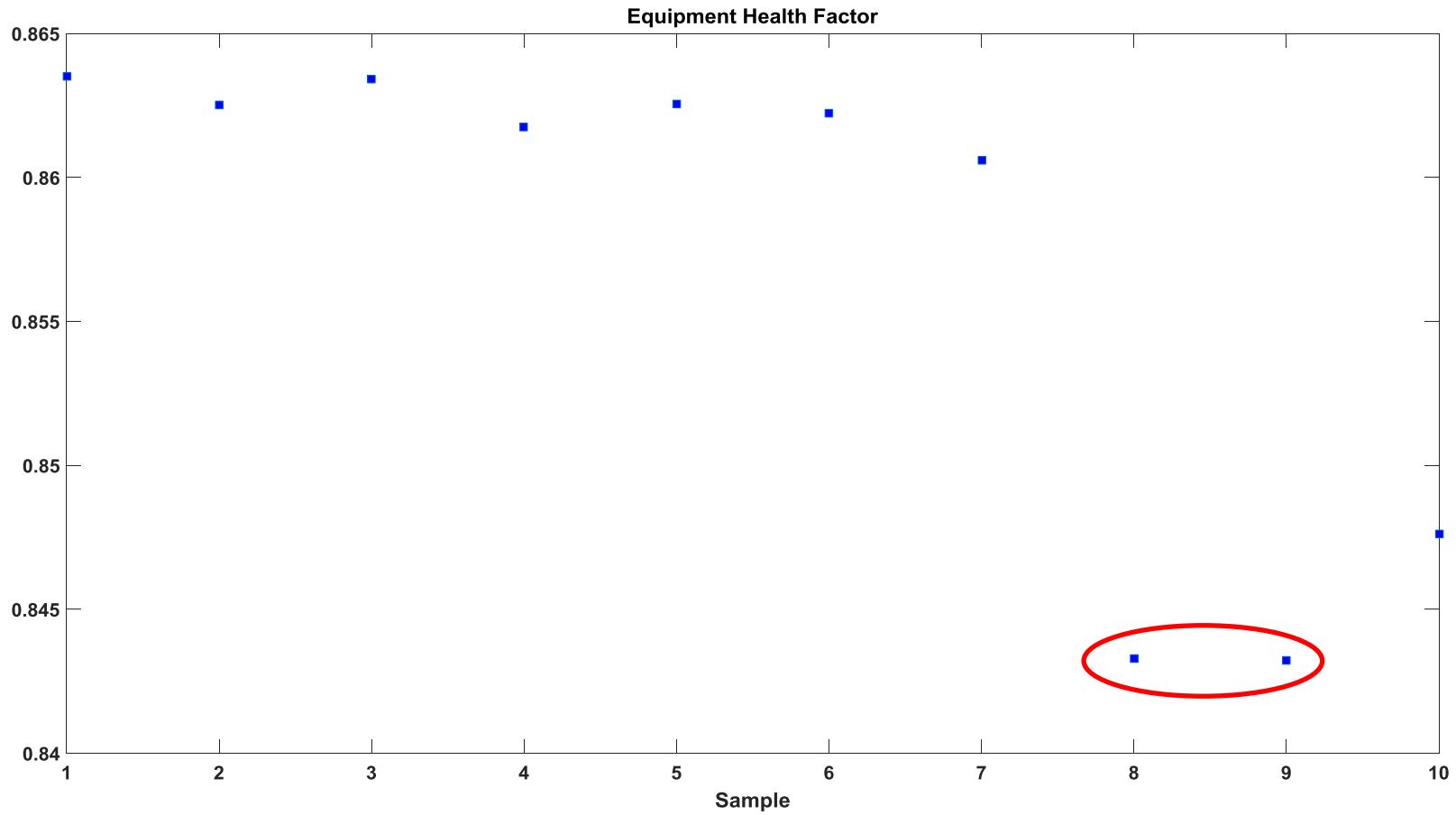


Characteristics of the new calculation method

- Averaging takes place at three levels:
 - Parameter level
 - Group level
 - Equipment level
- Drill-down ability through intermediate steps for root cause analysis
- “Bad” parameters can be detected at a glance without huge process knowledge
- Machine state average can be obtained
- EHF result is easier to interpret

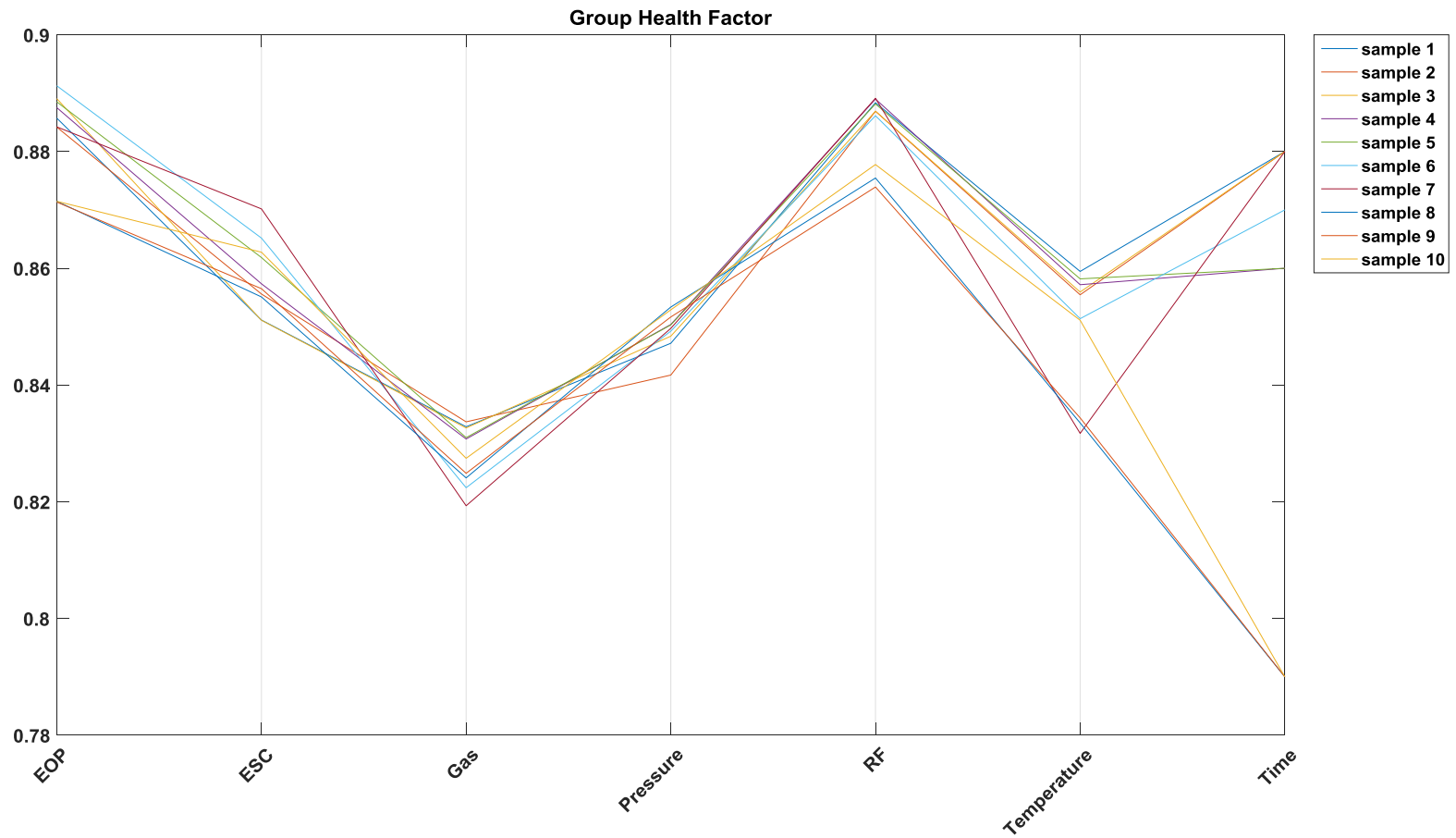
V. Application example

Equipment health factor level



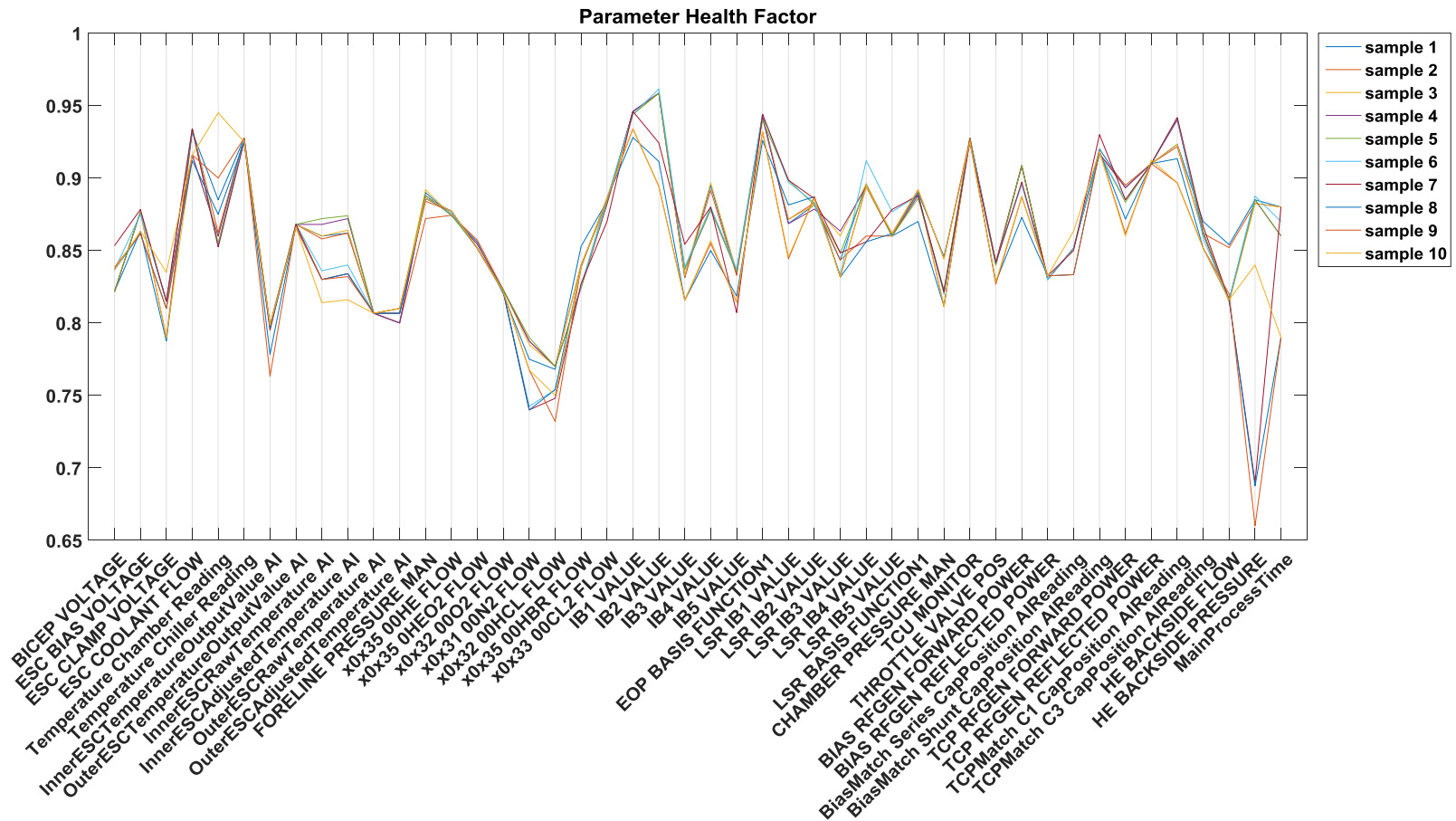
V. Application example

Group health factor level



V. Application example

Parameter health factor level



VI. Conclusion

- A general method for detection of unknown failures was developed
- Generic concept transferable to other processes
- Application of various feature extraction methods dependent on curve shape
- Extracted key features can be used for EHF calculation or other technologies to improve models
- Drill-down structure identifies underperforming components
- Desired benefit of EHF
 - Lower production costs
 - Improve production quality
 - Maintaining high yield

Acknowledgment

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- Project work-package partners:
 - Dresden University of Technology
 - Fraunhofer Institute for Integrated Systems and Device Technology
 - Infineon Technologies Austria AG
 - Infineon Technologies Dresden GmbH
 - SpeedUp Consulting

Thank you for listening!